

N-Channel Enhancement Mode MOSFET

Feature

- 200V/64A
 - 100% Avalanche Tested
- Reliable and Rugged
- Halogen Free and Green Devices Available (RoHS Compliant)

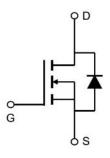
Applications

- Power Switching application
- Uninterruptible Power Supply

Pin Description



TO-247A-3L



N-Channel MOSFET

Ordering and Marking Information



Package Code

W :TO-247A-3L

Date Code XYMXXXXXX

Note: HUAYI lead-free products contain molding compounds/die attach materials and 100% matte tin plateTermi-Nation finish; which are fully compliant with RoHS. HUAYI lead-free products meet or exceed the lead-Free requirements of IPC/JEDEC J-STD-020 for MSL classification at lead-free peak reflow temperature. HUAYI defines "Green" to mean lead-free (RoHS compliant) and halogen free (Br or Cl does not exceed 900ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500ppm by weight).

HUAYI reserves the right to make changes, corrections, enhancements, modifications, and improvements to this pr-oduct and/or to this document at any time without notice.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit	
Common Rat	tings (Tc=25°C Unless Otherwise Noted)			
VDSS	Drain-Source Voltage		200	V
Vgss	Gate-Source Voltage		±20	V
TJ	Maximum Junction Temperature		175	°C
Tstg	Storage Temperature Range		-55 to 175	°C
ls	Source Current-Continuous(Body Diode)	Tc=25°C	64	А
Mounted on	Large Heat Sink		'	
I DМ	Pulsed Drain Current *	Tc=25°C	250	А
	Continuous Danis Courset	Tc=25°C	64	А
lσ	Continuous Drain Current	Tc=100°C	46	А
D	Mariana Barra Birainatian	Tc=25°C	263	W
P _D	Maximum Power Dissipation Tc=100°C		131	W
R₀JC	Thermal Resistance, Junction-to-Case		0.57	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient **		62	°C/W
Eas	Single Pulsed-Avalanche Energy ***	L=0.3mH	575	mJ

Note: * Repetitive rating; pulse width limited by max. junction temperature.

** Surface mounted on FR-4 board.

*** Limited by TJmax , starting TJ=25 $^{\circ}$ C, L = 0.3mH, VDS=100V, VGS =10V.

Electrical Characteristics (Tc = 25°C Unless Otherwise Noted)

O b. a.l	Damanatan	Took Oomeliking	HY1720			
Symbol	Parameter	Test Conditions	Min	Тур.	Max	Unit
Static Cha	racteristics					
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V,I _{DS} =250μA	200	-	_	V
	IDSS Drain-to-Source Leakage Current	V _{DS} =200V,V _{GS} =0V	-	-	1.0	μA
IDSS		TJ=125°C	-	-	50	μA
VGS(th)	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250μA	3.0	3.8	5.0	V
Igss	Gate-Source Leakage Current	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
RDS(ON)*	Drain-Source On-State Resistance	V _{GS} =10V,I _{DS} =30A	-	27	32	mΩ
Diode Cha	racteristics				•	
V _{SD} *	Diode Forward Voltage	Isp=30A,Vgs=0V	-	0.85	1.3	V
trr	Reverse Recovery Time	la==20	-	111.6	_	ns
Qrr	Reverse Recovery Charge	IsD=30A,dIsD/dt=100A/µs	-	581.9	-	nC



Electrical Characteristics (Cont.) (Tc =25°C Unless Otherwise Noted)

Cumbal	Downwood and	Took Conditions		HY1720		11:4
Symbol	Parameter	Test Conditions	Min	Тур.	Max	Unit
Dynamic	Characteristics		•			
Rg	Gate Resistance	V_{GS} =0V, V_{DS} =0V, F =1 MHz	-	3.4	-	Ω
Ciss	Input Capacitance	V _{GS} =0V,	-	4816	-	
Coss	Output Capacitance	V _{DS} =100V,	-	206	-	pF
Crss	Reverse Transfer Capacitance	Frequency=1.0MHz	-	120	-	
td(ON)	Turn-on Delay Time		-	27.6	-	
Tr	Turn-on Rise Time	$V_{DD}=100V,R_{G}=4\Omega,$	-	98.1	-	
td(OFF)	Turn-off Delay Time	los=30A,Vgs=10V	-	78.4	-	ns
Tf	Turn-off Fall Time		-	89.4	-	
Gate Cha	Gate Charge Characteristics					
Qg	Total Gate Charge	1/ -400// 1/ -40//	-	102	-	
Qgs	Gate-Source Charge	V_{DS} =100V, V_{GS} =10V, I_{D} =30A	-	29	-	nC
Qgd	Gate-Drain Charge	ID-30A	-	35	-	

Note: *Pulse test, pulse width ≤ 300 us, duty cycle $\leq 2\%$



Typical Operating Characteristics

Figure 1: Power Dissipation

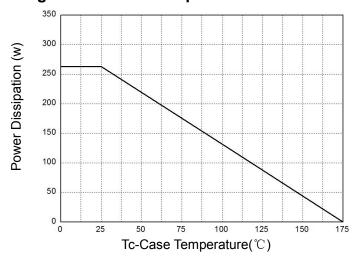


Figure 2: Drain Current

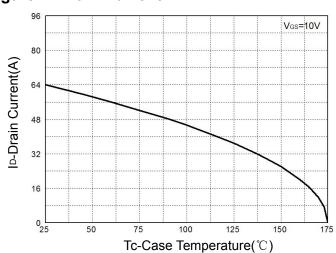


Figure 3: Safe Operation Area

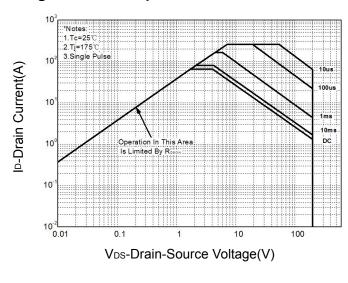


Figure 4: Thermal Transient Impedance

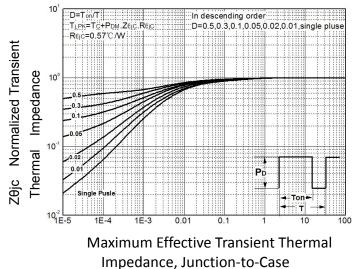


Figure 5: Output Characteristics

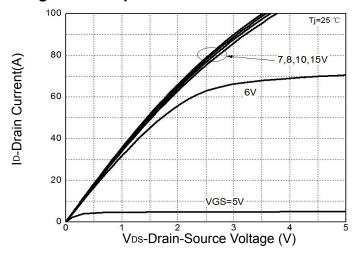
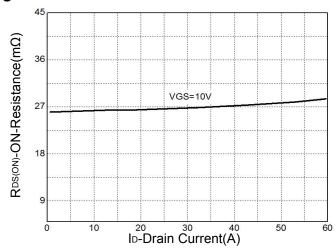


Figure 6: Drain-Source On Resistance





Typical Operating Characteristics(Cont.)

Figure 7: On-Resistance vs. Temperature

2.4

Poly 2.0

1.6

VGS=10V,IDS=30A

1.2

0.4

0.4

Tj-Junction Temperature (°C)

Figure 8: Source-Drain Diode Forward

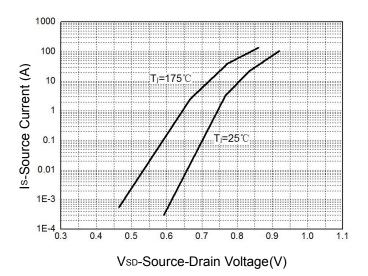


Figure 9: Capacitance Characteristics

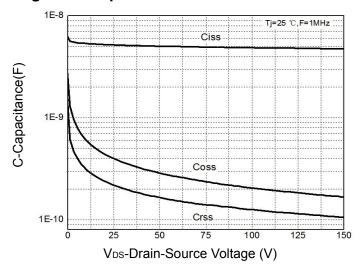
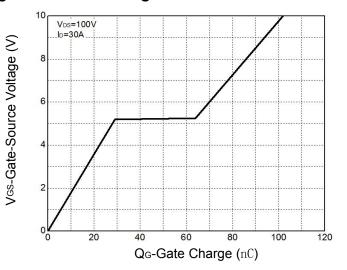
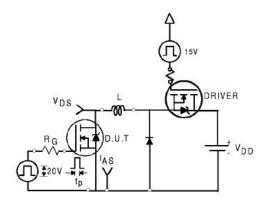


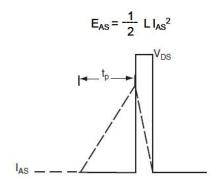
Figure 10: Gate Charge Characteristics



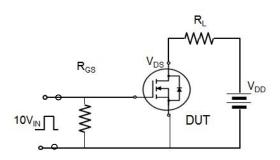


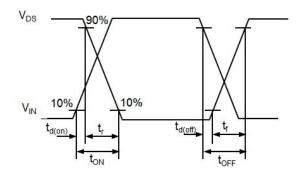
Avalanche Test Circuit



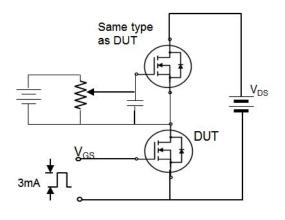


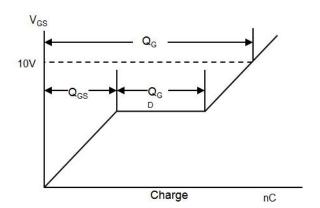
Switching Time Test Circuit





Gate Charge Test Circuit





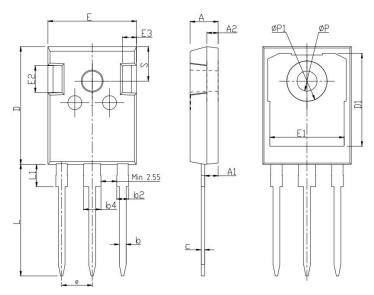


Device Per Unit

Package Type	Unit	Quantity
TO-247A-3L	Tube	30

Package Information

TO-247A-3L

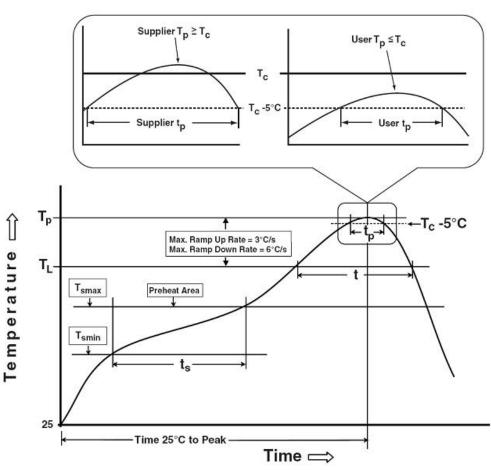


COMMON DIMENSIONS

CVMPOL	mm			
SYMBOL	MIN	NOM	MAX	
Α	4.80	5.00	5.20	
A1	2.21	2.41	2.61	
A2	1.85	2.00	2.15	
b	1.11	1.21	1.36	
b2	1.91	2.01	2.21	
b4	2.91	3.01	3.21	
С	0.51	0.61	0.75	
D	20.70	21.00	21.30	
D1	16.25	16.55	16.85	
Е	15.50	15.80	16.10	
E1	13.00	13.30	13.60	
E2	4.80	5.00	5.20	
E3	2.30	2.50	2.70	
е	5.44BSC			
L	19.62	19.92	20.22	
L1	-	-	4.30	
ФР	3.40	3.60	3.80	
ФР1	-	-	7.30	
S	6.15BSC			



Classification Profile



Classification Reflow Profiles

Sn-Pb Eutectic Assembly	Pb-Free Assembly
100 °C 150 °C 60-120 seconds	150 °C 200 °C 60-120 seconds
3 °C/second max.	3°C/second max.
183 °C	217 °C
60-150 seconds	60-150 seconds
See Classification Temp in table 1	SeeClassification Tempin table 2
20** seconds	30** seconds
6 °C/second max.	6 °C/second max.
6 minutes max. 8 minutes ma	
	100 °C 150 °C 60-120 seconds 3 °C/second max. 183 °C 60-150 seconds See Classification Temp in table 1 20** seconds 6 °C/second max.

^{*}Tolerance for peak profile Temperature (Tp) is defined as a supplier minimum and a user maximum.

^{**} Tolerance for time at peak profile temperature (tp) is defined as a supplier minimum and a user maximum.

HY1720W



Table 1.SnPb Eutectic Process – Classification Temperatures (Tc)

Package	Volume mm³	Volume mm³
Thickness	<350	≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2.Pb-free Process – Classification Temperatures (Tc)

Package	Volume mm ³	Volume mm³	Volume mm³
Thickness	<350	350-2000	≥2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	168/500/1000 Hrs, Bias @ 150°C
HTGB	JESD-22, A108	168 /500/1000Hrs, Vgs100% @ 150°C
PCT	JESD-22, A102	96 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -55°C~150°C

Customer Service

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